

ESREF 2018 Conference
 Provisional Programme
 Ver.09: 21-08-2018

Monday, October 1					Tuesday, October 2					Wednesday, October 3					Thursday, October 4					Friday, October 5		
Room A	Room B	Room C	Room D	Exhibition area	Room A	Room B	Room C	Room D	Exhibition area	Room A	Room B	Room C	Room D	Exhibition area	Room A	Room B	Room C	Room D	Exhibition area			
	TUTORIAL Reliability issues in power SiC and GaN			Exhibition set up	E1-2 (5)	A-1 (5)	K-2 (5)	Industrial session	Exhibition	E2-3 (4)	L-1 (4)	SS1-1 (4)	Industrial session	Exhibition	C-2 (5)	I-1 (5)	G (5)	ECPE Workshop: Frontiers in reliability engineering: railway traction, renewables, industry	Exhibition	Outing	Technical visit 1	Technical visit 2
	TUTORIAL Reliability of dielectric packages for power devices	TUTORIAL Dielectric reliability in microelectronics			Invited B. Linder					Coffee break	Invited F. Ahmann	Invited M.B. Tahooni			Coffee break							
				Lunch	E1-3 (3)	A-2 (3)	B1-1 (3)	Industrial session	Exhibition	F-2 (4)	L-2 (4)	SS1-2 (4)	Workshop: Reliability in innovative Automotive ICs	Exhibition	C-3 (5)	I-2 (5)	D (5)	Workshop: Condition and health monitoring	Exhibition			
	TUTORIAL Moisture Modelling in Complex Systems	TUTORIAL Introduction to the modern reliability		Exhibition set up	Invited J. Lutz	Invited N. Stojadinovic					Invited R. Ambat	Invited P. Platf			Closing Session					Lunch		
Invited speaker Keynote P. Gargani Keynote P.C. Kjaer					E2-1 (5)	A-3 (5)	B1-2 (3)	Industrial session	Exhibition	F-3 (5)	L-3 (4)	SS1-3 (5)	Workshop: Applied robustness variation	Exhibition	APETT Symposium					Exhibition dismantling		
				Coffee break	E2-2 (4)	H (4)	B3 (3)	Industrial session	Exhibition					APETT Symposium					Exhibition dismantling			
	E1-1 (3)	F-1 (3)	C-1 (3)	K-1 (2)	Poster session				Aalborg City buffet	Tour & Social dinner												
					Young Professional Reception																	

- Tracks**
- A - Quality and Reliability Assessment Techniques and Methods for Devices and Systems
 - B1 - Si-Technologies & Nanoelectronics: Hot Carriers, High-K, Gate Materials
 - B2 - Si-Technologies & Nanoelectronics: Low-K, Cu Interconnects
 - B3 - Si-Technologies & Nanoelectronics: ESD, EMI and Latch-up
 - C - Progress in Failure Analysis: Defect Detection and Analysis
 - D - Reliability of Microwave and Compound Semiconductors Devices
 - E1 - Power Devices Reliability - Silicon and Passive
 - E2 - Power Devices Reliability - Wide Bandgap Devices
 - F - Packaging and Assembly Reliability
 - G - MEMS, Sensors and Organic Electronics Reliability
 - H - Photonics Reliability
 - I - Extreme Environments and Radiation
 - K - Renewable Energies Reliability
 - L - Modeling for Reliability
 - SS1 - Reliability in Traction Applications